



033082M300

PATENT

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

**Yasuo KOBAYASHI, et al.**

Serial No.: 10/568,461

Filed : February 15, 2006

Art Unit : To Be Assigned

Examiner : To Be Assigned

For : SEMICONDUCTOR DEVICE, MANUFACTURING METHOD OF SEMICONDUCTOR  
DEVICE, AND GAS FOR PLASMA CVD PROCESS

**SECOND INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure under 37 C.F.R. 1.56, Applicants are enclosing an Information Disclosure Citation Form (PTO-1449) and a copy of the documents cited therein. These documents were cited on pages 1 and 2 of Applicants' specification.

It is respectfully requested that the cited documents be considered by the Examiner in the above-identified patent application and that the cited documents be made officially of record therein. It is further requested that a listing of the same appear on the face of any patent which may issue from this application.

This Information Disclosure Statement is being filed in advance of the receipt of a first Office Action in this application. Therefore, it is believed that no fees are due under 37 C.F.R. Section 1.97(b)(3).

Respectfully submitted,  
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Date: May 18, 2006



FORM PTO-1449 <b>INFORMATION DISCLOSURE STATEMENT</b>	ATTY. DOCKET <b>033082M300</b>	SERIAL NO. <b>10/568,461</b>
	APPLICANT: <b>Yasuo KOBAYASHI, et al.</b>	
	FILING DATE <b>February 15, 2006</b>	GROUP ART UNIT <b>To Be Assigned</b>

### U.S. PATENT DOCUMENTS

*Examiner's Initials		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE, IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						

### FOREIGN PATENT DOCUMENTS

*Examiner's Initials		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	AH	10-144675	5/29/98	Japan			Abstract	
	AI	2000-332001	11/30/00	Japan			Abstract	
	AJ	2002-220668	8/9/02	Japan			Abstract	
	AK	09-237783	9/9/97	Japan			Abstract	
	AL							
	AM							
	AN							
	AO							
	AP							

### OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	
AR	
AS	

EXAMINER:	DATE CONSIDERED:
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.